SCLS081B - DECEMBER 1982 - REVISED MAY 1997

 Package Options Include Plastic Small-Outline (D), Thin Shrink
Small-Outline (PW), and Ceramic Flat (W)
Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J)
300-mil DIPs

#### description

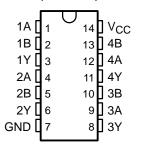
These devices contain four independent 2-input AND gates. They perform the Boolean function  $Y = A \bullet B$  or  $Y = \overline{A + B}$  in positive logic.

The SN54HC08 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74HC08 is characterized for operation from -40°C to 85°C.

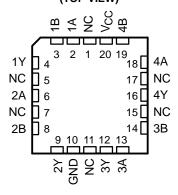
FUNCTION TABLE (each gate)

INP	UTS	OUTPUT
Α	В	Y
Н	Н	Н
L	Χ	L
Х	L	L

#### SN54HC08 . . . J OR W PACKAGE SN74HC08 . . . D, N, OR PW PACKAGE (TOP VIEW)

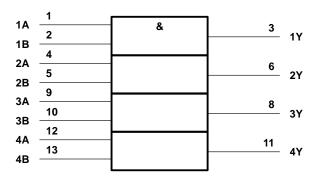


SN54HC08...FK PACKAGE (TOP VIEW)



NC - No internal connection

### logic symbol†



<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, N, PW, and W packages.

#### logic diagram (positive logic)





Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



## SN54HC08, SN74HC08 QUADRUPLE 2-INPUT POSITIVE-AND GATES

SCLS081B - DECEMBER 1982 - REVISED MAY 1997

### absolute maximum ratings over operating free-air temperature range†

Supply voltage range, V <sub>CC</sub>		0.5 V to 7	٧
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ ) (see	ee Note 1)	±20 m	١A
Output clamp current, IOK (VO < 0 or VO > VCO	c) (see Note 1)	±20 m	ıA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )		±25 m	١A
Continuous current through V <sub>CC</sub> or GND		±50 m	١A
Package thermal impedance, θ <sub>JA</sub> (see Note 2):	: D package	127°C/	W
-	N package	78°C/\	W
	PW package	170°C/	W
Storage temperature range, T <sub>sto</sub>	· · · · · · · · · · · · · · · · · · ·	-65°C to 150°	Ò,

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

#### recommended operating conditions

			S	SN54HC08			SN74HC08		
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage		2	5	6	2	5	6	V
		V <sub>CC</sub> = 2 V	1.5			1.5			
$V_{IH}$	High-level input voltage	V <sub>CC</sub> = 4.5 V	3.15			3.15			V
		VCC = 6 V	4.2			4.2			
VIL		V <sub>CC</sub> = 2 V	0		0.5	0		0.5	
	Low-level input voltage	V <sub>CC</sub> = 4.5 V	0		1.35	0		1.35	V
		VCC = 6 V	0		1.8	0		1.8	
٧ <sub>I</sub>	Input voltage		0		VCC	0		VCC	V
۷o	Output voltage		0		VCC	0		Vcc	V
t <sub>t</sub>		V <sub>CC</sub> = 2 V	0		1000	0		1000	
	Input transition (rise and fall) time	V <sub>CC</sub> = 4.5 V	0		500	0		500	ns
		VCC = 6 V	0		400	0		400	
TA	Operating free-air temperature	•	-55		125	-40		85	°C



SCLS081B - DECEMBER 1982 - REVISED MAY 1997

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	PARAMETER TEST CONDITIONS		vcc	Т	A = 25°C	;	SN54HC08		SN74HC08		UNIT
PARAMETER				MIN	TYP	MAX	MIN	MAX	MIN	MAX	ONII
			2 V	1.9	1.998		1.9		1.9		
		I <sub>OH</sub> = -20 μA	4.5 V	4.4	4.499		4.4		4.4		
Voн	VI = VIH or VIL		6 V	5.9	5.999		5.9		5.9		V
		$I_{OH} = -4 \text{ mA}$	4.5 V	3.98	4.3		3.7		3.84		
		$I_{OH} = -5.2 \text{ mA}$	6 V	5.48	5.8		5.2		5.34		
			2 V		0.002	0.1		0.1		0.1	
		$I_{OL} = 20  \mu A$	4.5 V		0.001	0.1		0.1		0.1	
VOL	VI = VIH or VIL		6 V		0.001	0.1		0.1		0.1	V
		$I_{OL} = 4 \text{ mA}$	4.5 V		0.17	0.26		0.4		0.33	
		$I_{OL} = 5.2 \text{ mA}$	6 V		0.15	0.26		0.4		0.33	
lį	$V_I = V_{CC}$ or 0		6 V		±0.1	±100		±1000		±1000	nA
Icc	$V_I = V_{CC}$ or 0,	I <sub>O</sub> = 0	6 V			2		40		20	μΑ
C <sub>i</sub>			2 V to 6 V		3	10		10		10	pF

# switching characteristics over recommended operating free-air temperature range, $C_L$ = 50 pF (unless otherwise noted) (see Figure 1)

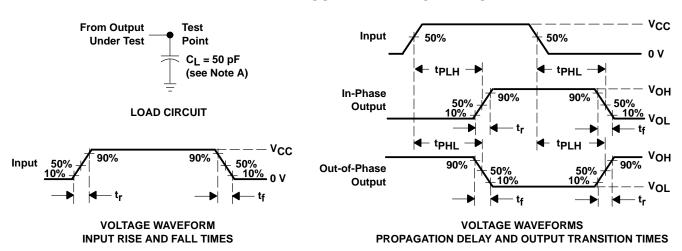
PARAMETER	FROM	TO (OUTPUT)	V	T <sub>A</sub> = 25°C			SN54HC08		SN74HC08		UNIT
PARAMETER	(INPUT)		Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
	A or B	Υ	2 V		50	100		150		125	
t <sub>pd</sub>			4.5 V		10	20		30		25	ns
			6 V		8	17		25		21	
	Y		2 V		38	75		110		95	
t <sub>t</sub>		4.5 V		8	15		22		19	ns	
			6 V		6	13		19		16	

# operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance per gate	No load	20	pF

SCLS081B - DECEMBER 1982 - REVISED MAY 1997

#### PARAMETER MEASUREMENT INFORMATION



NOTES: A.  $C_L$  includes probe and test-fixture capacitance.

- B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \ \Omega$ ,  $t_f = 6 \ ns$ ,  $t_f = 6 \ ns$ .
- C. The outputs are measured one at a time with one input transition per measurement.
- D. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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